

FDR856P

P-Channel Logic Level Enhancement Mode Field Effect Transistor

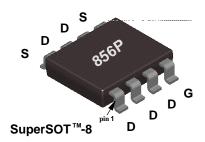
General Description

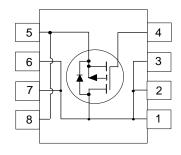
SuperSOT[™]-8 P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as battery powered circuits or portable electronics where low in-line power loss, fast switching and resistance to transients are needed.

Features

- = -6.3 A, -30 V, R $_{\rm DS(ON)}$ =0.025 Ω @ V $_{\rm GS}$ = -10 V $R _{\rm DS(ON)}$ =0.040 Ω @ V $_{\rm GS}$ = -4.5 V.
- SuperSOTTM-8 package: small footprint (40% less than SO-8);low profile (1mm thick);maximum power comperable to SO-8.
- High density cell design for extremely low R_{DS(ON)}.







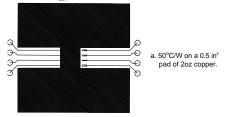
Absolute Maximum Ratings $T_A = 25^{\circ}C$ unless other wise noted

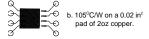
Symbol	Parameter		FDR856P	Units		
V _{DSS}	Drain-Source Voltage		-30			
V _{GSS}	Gate-Source Voltage - Continuous		±20	V		
D	Maximum Drain Current - Continuou	S (Note 1a)	-5.1	А		
	- Pulsed		-50			
P _D Maximum Power Dissipation	(Note 1a)	1.8	W			
		(Note 1b)	1			
		(Note 1c)	0.9			
$\Gamma_{\rm J}$, $T_{\rm STG}$	Operating and Storage Temperature	Range	-55 to 150	℃		
THERMA	L CHARACTERISTICS	·		·		
$R_{\theta JA}$	Thermal Resistance, Junction-to-Am	ibient (Note 1a)	50	°C/W		
R _{euc}	Thermal Resistance, Junction-to-Ca	SE (Note 1)	25	°C/W		

Symbol	Parameter	Conditions	Min	Тур	Max	Units
OFF CHAR	ACTERISTICS		•			
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-30			V
Δ BV _{DSS} / Δ T _J	Breakdown Voltage Temp. Coefficient	I_D = -250 μ A, Referenced to 25 $^{\circ}$	С	-15		mV /°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -24 \text{ V}, \ V_{GS} = 0 \text{ V}$			-1	μA
		$T_J =$	55°C		-10	μΑ
I _{GSSF}	Gate - Body Leakage, Forward	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
	CTERISTICS (Note 2)	·				
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-1	-1.5	-3	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Temp. Coefficient	I_D = -250 μ A, Referenced to 25 $^{\circ}$	С	3		mV /°C
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = -10 \text{ V}, I_{D} = -6.3 \text{ A}$		0.022	0.025	Ω
		T _J =	125°C	0.03	0.042	
		$V_{GS} = -4.5 \text{ V}, I_{D} = -5 \text{ A}$		0.033	0.04	
I _{D(ON)}	On-State Drain Current	$V_{GS} = -10 \text{ V}, \ V_{DS} = -5 \text{ V}$	-50			Α
g _{FS}	Forward Transconductance	$V_{DS} = -10 \text{ V}, I_{D} = -6.3 \text{ A}$		15		S
DYNAMIC	CHARACTERISTICS					
C _{iss}	Input Capacitance		1370		pF	
C _{oss}	Output Capacitance	f = 1.0 MHz		740		pF
C _{rss}	Reverse Transfer Capacitance			220		pF
SWITCHING	G CHARACTERISTICS (Note 2)			•		
t _{D(on)}	Turn - On Delay Time	$V_{DS} = -15 \text{ V}, I_{D} = -1 \text{ A}$		7	14	ns
t _r	Turn - On Rise Time	$V_{GS} = -10 \text{ V}$, $R_{G} = 6 \Omega$		12	19	ns
t _{D(off)}	Turn - Off Delay Time			80	100	ns
t _f	Turn - Off Fall Time			130	160	ns
Q_g	Total Gate Charge	$V_{DS} = -15 \text{ V}, \ I_{D} = -6.3 \text{ A},$		22	31	nC
Q_{gs}	Gate-Source Charge	V _{GS} = -10 V		3.8		nC
Q_{gd}	Gate-Drain Charge		8.7		nC	
DRAIN-SO	JRCE DIODE CHARACTERISTICS AND MA	XIMUM RATINGS		_		
l _s	Maximum Continuous Drain-Source Diode F			-1.3	Α	
V _{SD}	Drain-Source Diode Forward Voltage	Drain-Source Diode Forward Voltage $V_{GS} = 0 \text{ V}, I_{S} = -1.3 \text{ A} \text{ (Note 2)}$				

Notes:

1. R_{8.u.} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{8.c.} is guaranteed by design while R_{8.c.} is determined by the user's board design.







Scale 1 : 1 on letter size paper 2. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%.

Typical Electrical Characteristics

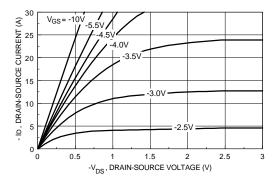


Figure 1. On-Region Characteristics.

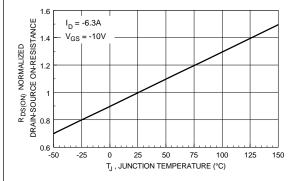


Figure 3. On-Resistance Variation with Temperature.

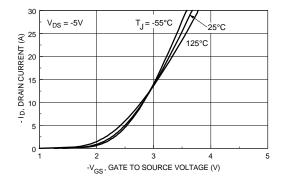


Figure 5 . Transfer Characteristics.

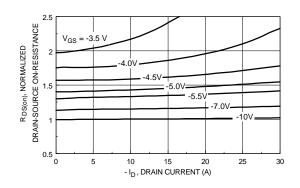


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

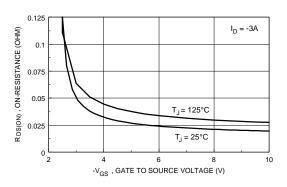


Figure 4 . On Resistance Variation with Gate-to-Source Voltage.

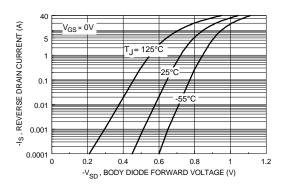


Figure 6 . Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Electrical Characteristics (continued)

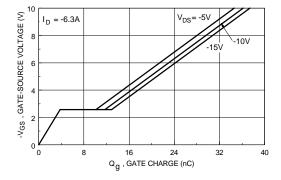


Figure 7. Gate Charge Characteristics.

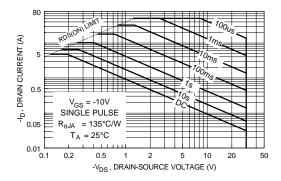


Figure 9. Maximum Safe Operating Area.

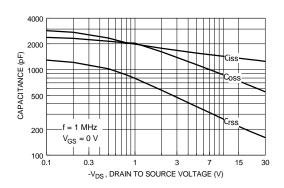


Figure 8. Capacitance Characteristics.

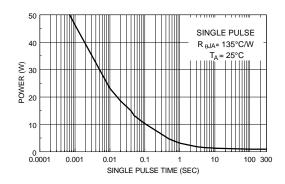


Figure 10. Single Pulse Maximum Power Dissipation.

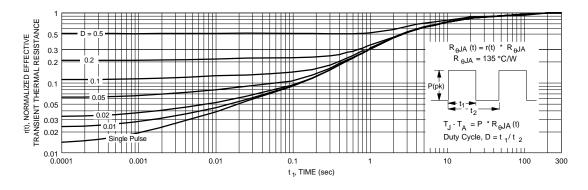
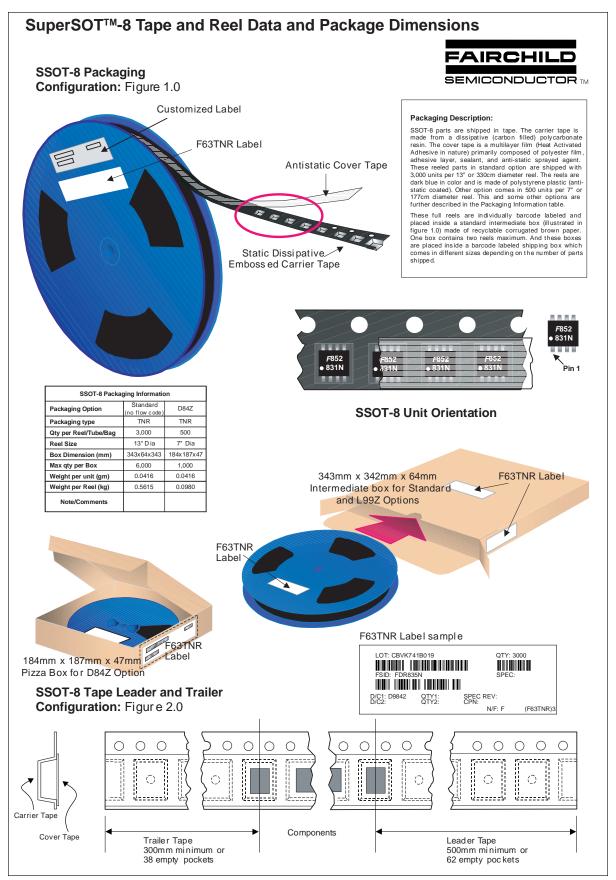
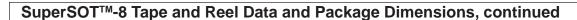


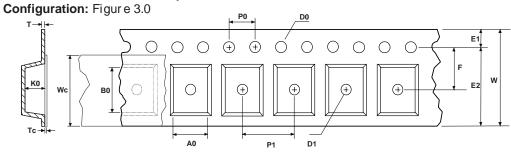
Figure 11. Transient Thermal Response Curve.

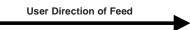
Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.





SSOT-8 Embossed Carrier Tape



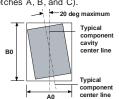


	Dimensions are in millimeter													
Pkg type	A0	В0	w	D0	D1	E1	E2	F	P1	P0	K0	Т	Wc	Тс
SSOT-8 (12mm)	4.47 +/-0.10	5.00 +/-0.10	12.0 +/-0.3	1.55 +/-0.05	1.50 +/-0.10	1.75 +/-0.10	10.25 min	5.50 +/-0.05	8.0 +/-0.1	4.0 +/-0.1	1.37 +/-0.10	0.280 +/-0.150	9.5 +/-0.025	0.06 +/-0.02

Notes: A0, B0, and K0 dimensions are determined with respect to the EIA/Jedec RS-481 rotational and lateral movement requirements (see sketches A, B, and C).



Sketch A (Side or Front Sectional View)
Component Rotation

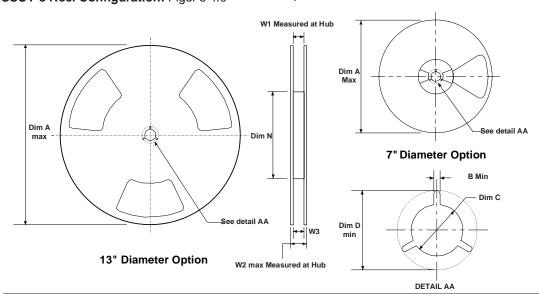


Sketch B (Top View)
Component Rotation



Sketch C (Top View)
Component lateral movement

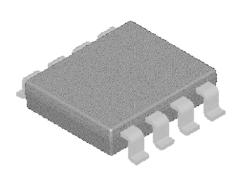
SSOT-8 Reel Configuration: Figur e 4.0

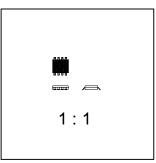


	Dimensions are in inches and millimeters									
Tape Size	Reel Option	Dim A	Dim B	Dim C	Dim D	Dim N	Dim W1	Dim W2	Dim W3 (LSL-USL)	
12mm	7" Dia	7.00 177.8	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	5.906 150	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4	
12mm	13" Dia	13.00 330	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	7.00 178	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4	

SuperSOT™-8 Tape and Reel Data and Package Dimensions, continued

SuperSOT™-8 (FS PKG Code 34, 35)

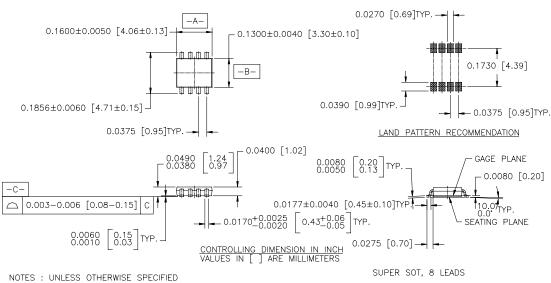




Scale 1:1 on letter size paper

Dimensions shown below are in: inches [millimeters]

Part Weight per unit (gram): 0.0416



STANDARD LEAD FINISH TI BE 200 MICROINCHES / 5.08 MICROMETERS MINIMUM TIN/LEAD (SOLDER) ON COPPER.

2. NO JEDEC REGISTRATION AS JAN. 1996

TRADEMARKS

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

FACT $^{\text{TM}}$ QFET $^{\text{TM}}$ FACT Quiet Series $^{\text{TM}}$ QS $^{\text{TM}}$

 $\begin{array}{lll} \mathsf{FAST}^{\circledast} & \mathsf{Quiet}\,\mathsf{Series^{\mathsf{TM}}} \\ \mathsf{FASTr^{\mathsf{TM}}} & \mathsf{SuperSOT^{\mathsf{TM}}\text{-}3} \\ \mathsf{GTO^{\mathsf{TM}}} & \mathsf{SuperSOT^{\mathsf{TM}}\text{-}6} \\ \mathsf{HiSeC^{\mathsf{TM}}} & \mathsf{SuperSOT^{\mathsf{TM}}\text{-}8} \\ \end{array}$

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.
- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.